

**Notice of References Cited**

Application/Control No.

09/683,642

Applicant(s)/Patent Under  
Reexamination  
SHIGAPOV ET AL.

Examiner

Diem Tran

Art Unit

3748

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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Page 1 of 1

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